Application/Control No. 10/827,222 Examiner Mark S. Graham Applicatiot(s)/Patent Under Reexamination CHANG, WEN I. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*	:	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,336,942	06-1982	Warehime, Norwood R.	473/470
	В	US-6,312,343 B1	11-2001	Cho, Kwang H.	473/197
	С	US-6,352,480 B1	03-2002	Macaluso, Anthony G.	473/197
	D	US-6,514,149 B2	02-2003	Yoon, Young W.	473/197
	Е	US-6,517,444 B1	02-2003	Yoon, Young W.	473/197
	F	US-5,163,461 A	11-1992	Ivanovich et al.	135/126
	. G	US-5,427,381 A	06-1995	Macaluso et al.	273/400
	Н	US-5,569,094 A	10-1996	Macaluso, Anthony G.	473/197
	1	US-3,115,340	12-1963	STASIUK MITCHELL D	473/414
	J	US-6,607,455 B1	08-2003	Petras, Kenneth A.	473/478
	к	US-2003/0181264 A1	09-2003	Yoon, Young W.	473/421
	L	US-2001/0034271 A1	10-2001	Nozato, Kazu	473/197
	М	US-			

FOREIGN PATENT DOCUMENTS

*	4	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			·		
	0					
	Ρ					
	o'					
	R				·	
	S					
	. T				· .	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	: . U				
	V				
	w				
	×				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.